

<b>Notice of References Cited</b>	Application/Control No. 10/760,281	Applicant(s)/Patent Under Reexamination CHEN ET AL.	
	Examiner Adam C. Rehm	Art Unit 2875	Page 1 of 1

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*	C	US-6,857,767	02-2005	Matsui et al.	362/373
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**NON-PATENT DOCUMENTS**

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